

28<sup>th</sup> September – October 2<sup>nd</sup>, 2009 Saltillo (Coahuila) Mexico

## First Announcement

Dear Colleagues:

On behalf of the organizing committee it is with great pleasure, we invite you to participate in the **First Joint Advanced Electron Microscopy School and Workshop on Nanomaterials (AEM-NANOMAT'09)**, to be held at the Research Center for Applied Chemistry (CIQA) in Saltillo, Coahuila Mexico from 28th September to October 2nd 2009 in Saltillo Mexico. The AEM-NANOMAT is organized by the *Laboratory of Microscopy* at the Research Center for Applied Chemistry (CIQA) in collaboration with the Mexican Microscopy Association and the Nanotechnology Node Network of Coahuila State.

Attendance at this meeting will allow you to:

- Learn from internationally renowned researchers and experts in a comprehensive program covering the latest developments in Advanced Electron Microscopy techniques for Nanomaterials: Scanning and Transmission Electron Microscopy as well as specimen preparation using a Dual-Beam (SEM/FIB) system.
- Present your latest research in oral and poster sessions. The AEM-NANOMAT organization provides the opportunity to attend ONLY to the Workshop on Nanomaterials.
- Interact and promote scientific exchanges with interdisciplinary colleagues that are interested on recent developments in all branches of fundamental and applied Nanotechnology and Nanomaterials.

The AEM-NANOMAT will focus on the following topics:

### Advanced Electron Microscopy:

- Electron Diffraction: Electron crystallography
- HRTEM-HRSTEM: Quantitative analysis from the high resolution electron microscopy
- DUAL BEAM (SEM-FIB): specimen preparation and nanomachining
- Field emission gun for SEM and STEM: in-lens, low angle and others detectors

### Workshop on Nanomaterials:

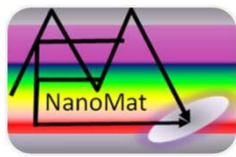
- Multifunctional Nanocomposites
- Electronic and magnetic materials
- Smart materials
- Nanoparticles: synthesis and applications
- Microbeam Analysis Characterization
- Structure phenomena and modeling
- Growth of thin films
- Semiconductors and optoelectronic materials
- Other Nanomaterials and Interdisciplinary Topics



The AEM School program will include keynote and invited lectures, as well as experimental session. Moreover, it will address state of the art topics, practical problems and solutions in the physics and chemistry of Nanomaterials. **Participation of young scientists and postgraduate students is encouraged.**

All the participants in the AEM-NANOMAT'09 can publish their full articles in a specialized volume of Materials Science Forum (<http://www.scientific.net/MSE>), which covers all areas of Materials Science, Solid State Physics and Solid State Chemistry and is indexed by the Journal Citation Reports.




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**Important dates and deadlines**

- **31 July 2009:** Deadline for abstract submission
- **07 August 2009:** Abstract acceptance notification
- **28 August 2009:** Author registration and manuscript submission deadline

AEM School		Workshop on Nanomaterials	
<b>Monday</b>	-Dual Beam-specimen interactions: FIB and Field Emission Gun (FEG) applications and TEM specimens preparation -Field emission gun for SEM and STEM: in-lens, low angle and others detectors <b>Theory and experimental demonstration: Dual-Beam Quanta 3D*</b> <b>Theory and experimental demonstration: scanning electron microscope FEG-STEM JSM 7401F*</b> <small>*the demonstrations will be held at the <u>Laboratory for Electron Microscopy (building G)</u> permanently open the monday and tuesday</small>	<b>Thursday</b>	<b>Symposia I</b> <ul style="list-style-type: none"> <li>• Multifunctional Nanocomposites</li> <li>• Electronic and magnetic materials</li> <li>• Smart materials</li> </ul> <b>Symposia II</b> <ul style="list-style-type: none"> <li>• Structure phenomena and modeling</li> <li>• Other Nanomaterials and Interdisciplinary Topics</li> </ul>
<b>Tuesday</b>	-High resolution electron microscopy in transmission (HRTEM) and scanning-transmission (HAADF-STEM) modes -Electron Diffraction, contrast diffraction, simulation and image analysis	<b>Friday</b>	<b>Symposia III</b> <ul style="list-style-type: none"> <li>• Nanoparticles: synthesis and applications</li> <li>• Microbeam Analysis Characterization</li> <li>• Growth of thin films</li> </ul> <b>Symposia IV</b> <ul style="list-style-type: none"> <li>• Semiconductors and optoelectronic materials</li> <li>• Other Nanomaterials and Interdisciplinary Topics</li> </ul>
<b>Wednesday</b>	<b>Theory and experimental remote operation of the Titan 80-300 kV</b> <b>Theory and experimental remote operation of the JEM-2200FS (Cs corrector and Omega filter)</b>		

**Arturo Ponce**

On behalf of the Organizing Committee

**1<sup>st</sup> Joint Advanced Electron Microscopy and Workshop on Nanomaterials**

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We make it visible.